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High Temperature Dielectric Ceramics: a review of temperature-stable high-permittivity perovskites.

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Abstract

Recent developments are reviewed in the search for dielectric ceramics which can operate at temperatures $> 200^{\circ}\text{C}$, well above the limit of existing high volumetric efficiency capacitor materials. Compositional systems based on lead-free relaxor dielectrics with mixed cation site occupancy on the perovskite lattice are summarised, and properties compared. As a consequence of increased dielectric peak broadening and shifts to peak temperatures, properties can be engineered such that a plateau in relative permittivity-temperature response (ϵ_r -T) is obtained, giving a $\pm 15\%$, or better, consistency in ϵ_r over a wide temperature range. Materials with extended upper temperature limits of 300°C , 400°C and indeed 500°C are grouped in this article according to the parent component of the solid solution, for example BaTiO_3 and $\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$. Challenges are highlighted in achieving a lower working temperature of -55°C , whilst also extending the upper temperature limit of stable ϵ_r to $\geq 300^{\circ}\text{C}$, and achieving high-permittivity and low values of dielectric loss tangent, $\tan\delta$. Summary tables and diagrams are used to help compare values of ϵ_r , $\tan\delta$, and temperature ranges of stability for different materials.

1. Introduction

This review presents a perspective on recent research into lead-free dielectric ceramics with high and stable relative permittivity, ϵ_r , to temperatures $>> 200^{\circ}\text{C}$, well-beyond the operating limit of traditional high ϵ_r (Class II) dielectrics based on ferroelectric BaTiO_3 .

The search for new and improved capacitor materials is driven by the growing demands of power electronics, where heat dissipation is an issue, and for electronics operating in harsh environments. New types of capacitor would find applications in the conversion and control of electrical energy, for example the integration of renewable energy sources with the grid, and inverters for electric and hybrid vehicles. Examples of harsh environment electronics include distributed control and sensing systems in aviation and aerospace, where electronic controls are placed close to the engine, at temperatures of 200 – 300°C . This reduces interconnections, saving hundreds of kilograms of aircraft weight and increasing the reliability of the system [1, 2]. The move to mechatronics in the automotive

sector requires sensing and control electronics to operate close to heat sources greater than 200°C, whilst temperature ranges for combustion sensing are 200–300°C, and for exhaust sensing $\geq 500^\circ$ [3]. Down-hole drilling in the oil and gas industries uses electronics and sensors to steer the drilling equipment and monitor its health: the geothermal gradient is $\geq 25^\circ\text{C}/\text{km}$, and in the past, drilling operations only reached temperatures of 150°C to 175°C, but advancing technology has made it feasible for the oil industry to drill deeper, requiring electronics that can operate reliably at higher temperatures [1, 3].

The lack of reliable high temperature, high volumetric efficiency capacitor materials, has curtailed growth in high temperature electronics [4]. Hence there is a growing awareness of the importance of research targeting the discovery and development of new, Class II robust dielectric materials. Advances in other key aspects of high temperature electronic systems, namely semiconductor and packaging materials, have resulted in components that can sustain prolonged exposure at 200–300°C. Indeed, silicon carbide and gallium nitride wide band-gap semiconductors have been demonstrated to 300–500°C [5, 6]. Likewise interconnects and packaging can cope with temperatures $> 200^\circ\text{C}$. By contrast, commercial dielectrics, based on ferroelectric BaTiO_3 are restricted to below 200°C. Moreover, polymer, glass or tantalum dielectrics are also generally specified only to $\sim 200^\circ\text{C}$. Lead-containing dielectric ceramics operate to ~ 200 – 250°C but their future use is uncertain due to environmental legislation [7, 8]. Major advances have already been made in low-permittivity Class 1 dielectric ceramics; Kemet Electronics have pioneered COG base-metal-electrode multilayer capacitors with remarkably stable performance to 200°C and above, but these materials are not designed for high energy storage density applications [3, 9].

Given existing limitations, the development of improved, device-quality Class II high temperature, high storage density dielectrics with stable performance over wide temperature ranges to $\geq 300^\circ\text{C}$ would be transformative, and open up new opportunities in energy generation and transmission, the low carbon economy, and control and sensing electronics in aerospace, aviation and automotive industries.

The Electronic Industries Alliance categorises Class II capacitors according to: lower operating temperature; upper operating temperature; level of stability in capacitance - as described in Table 1. The code X7R, for example, represents dielectrics specified from -55°C to 125°C with variability in capacitance of within $\pm 15\%$. This level of performance is achieved through doping ferroelectric BaTiO_3 , with Co, Nb or other elements, to develop core-shell segregated grain structures which result in a smearing of the Curie peak at the ferroelectric-paraelectric transition temperature, T_c which occurs at $\sim 130^\circ\text{C}$ in unmodified BaTiO_3 . Other chemical modifications to BaTiO_3 extend the upper limit to 175°C (X9R).

Table1. EIA standard specification codes for class II types dielectrics for capacitor applications

1st Letter		Numeric		2nd Letter	
Symbol	Low Temperature Limit ($^\circ\text{C}$)	Symbol	High Temperature Limit ($^\circ\text{C}$)	symbol	Maximum % variation in Capacitance
Z	+10	4	+65	A	± 1.0
Y	-30	5	+85	B	± 1.5
X	-55	6	+105	C	± 2.2
		7	+125	D	± 3.3

		8	+150	E	±4.7
		9	+175	F	±7.5
				P	±10.0
				R	±15.0
				S	±22.0

Numerous complex ceramic solid solution systems have been reported which display frequency dependent, broad ϵ_r -T peaks characteristic of a relaxor dielectric, and over narrow compositional ranges a ϵ_r -T plateau develops, extending to well above 200°C. These materials are referred to as ‘temperature-stable relaxor dielectrics’, and offer promise for developing new Class II capacitor materials which can operate to much higher temperatures than traditional X7R-X9R ferroelectric-based dielectrics. In a classic relaxor such as lead magnesium niobate, $\text{Pb}(\text{Mg}_{1/3}\text{Nb}_{2/3})\text{O}_3$, the ϵ_r -T response exhibits broad frequency-dependent ϵ_r peaks at a temperature denoted T_m [10–12]. Structural models to explain the dielectric properties of relaxors are generally based on the effect of mixed valence occupancy in disrupting long-range (ferroelectric) polar order, resulting in polar nanoregions, as in B-site disorder on the ABO_3 perovskite structure of $\text{Pb}(\text{Mg}_{1/3}\text{Nb}_{2/3})\text{O}_3$ [13, 14]. The broad frequency dependent ϵ_r peak characteristic of a relaxor, Figure 1, is thought to originate from temperature-dependent changes in the length scales and coupling dynamics of polar nanoregions.

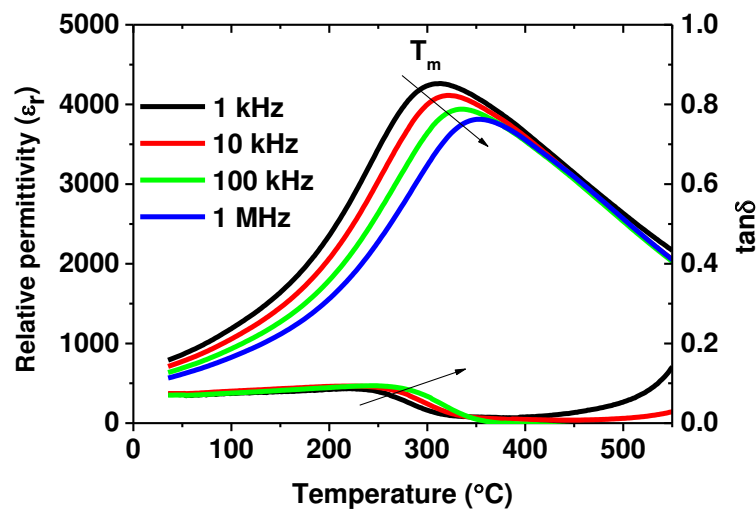


Figure 1. Frequency dependent ϵ_r peak, and $\tan\delta$ dispersion, in a relaxor dielectric $0.9\text{K}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-}0.1\text{BaZr}_{0.2}\text{Ti}_{0.8}\text{O}_3$ [15]

An example is shown in Figure 2 of how a diffuse ϵ_r relaxor peak can be further broadened and suppressed by additional cation substitutions on A and B sites of the ABO_3 lattice to develop a temperature-insensitive $\epsilon_r(T)$ plateau. The region of stable ϵ_r (defined as $\epsilon_{r,\text{mid}} \pm 15\%$ or better) generally has a lower temperature limit slightly below the original T_m and an upper limit at the onset of sharp increases to dielectric loss (or electronic conduction).

The mechanisms leading to conversion of a classic relaxor to a temperature-stable relaxor lie outside the scope of this review. Indeed little is known as to the chemical or structural origins, other than loose empirical correlations between mixed site occupancy levels

and the suppression of the ϵ_r peak. It may be that lattice scale heterogeneity suppresses the normal changes in polar structure/coupling on cooling from the Burns temperature through the ergodic region [17], as in the example of $\text{Ba}_{0.8}\text{Ca}_{0.2}\text{TiO}_3\text{-Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$, where the anticipated A site ions are Ba^{2+} , Ca^{2+} , Bi^{3+} and the B sites, Mg^{2+} , Ti^{4+} (Ca^{2+}) [16]. Unlike ferroelectric based X7R dielectrics, strong evidence of core-shell segregation is not visible in electron micrographs of high temperature analogues; it may be a factor but if so involve more subtle compositional variations and/or involve chemical heterogeneity over shorter length scales. Future work to examine the possibility that clustering of specific cations occurs on a nanoscale, over dimensions of a few unit cells, could give valuable insights into factors that may contribute to fluctuations in local electric and elastic fields that moderate and suppress normal relaxor $\epsilon_r(T)$ behaviour.

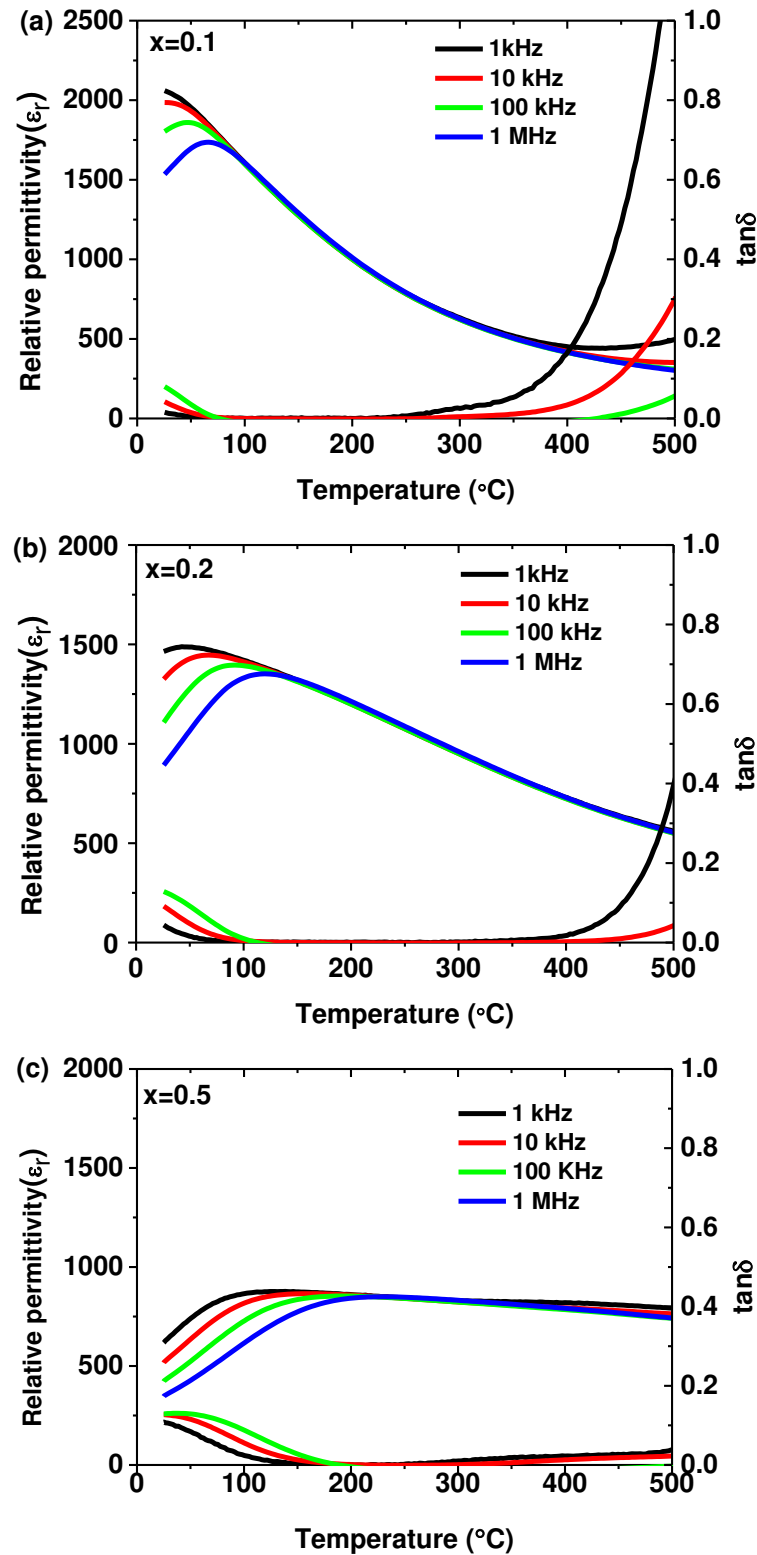


Figure 2. Progression in ϵ_r -T response from (a,b) normal relaxor to (c) a temperature-stable relaxor by increasing the level of mixed cation substitution for the system, $(1-x)\text{Ba}_{0.8}\text{Ca}_{0.2}\text{TiO}_3-x\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$: (a) $x = 0.1$; (b) $x = 0.2$; (c) $x = 0.5$ [16].

This review focusses on basic dielectric parameters of ceramic compositions that offer promise as high volumetric efficiency Class II capacitor materials. Relative permittivity ϵ_r ,

loss tangent $\tan\delta$ and electrical resistivity versus temperature are described and compared (ϵ_r and $\tan\delta$ are generally quoted for measurements at 1 kHz). Where available, data on RC time constant and energy storage density are also presented. These basic parameters in themselves do not confirm that a particular material is a suitable capacitor material. However they do enable the most promising dielectric materials to be screened and selected for follow on capacitor-grade evaluation trials. The latter would require fabrication of ceramic layers and multi-layers for testing of insulation resistance, dielectric breakdown strength, voltage coefficient, energy density, power density, dc degradation etc., involving highly accelerated life testing (HALT).

The value and temperature range of stability in relative permittivity is a helpful basic comparison point to assess materials being considered as high temperature dielectrics. Claims of a wide working temperature range based solely on temperature range of stable ϵ_r may be misleading, should dielectric losses or electrical conductivity rise above acceptable limits. A reasonable benchmark for ‘low dielectric loss’ is taken in this review to correspond to $\tan\delta \leq 0.02(5)$. It is also important to scrutinise if a reported wide temperature range of stable ϵ_r refers to overlapping temperature ranges of multiple compositions in a solid solution series: it should of course only refer to one specific material i.e. one solid solution composition.

As mentioned above, the two main categories of perovskite ceramics in which temperature-stable dielectric relaxor characteristics with consistency in $\epsilon_r \pm 15\%$ over wide ranges of temperature extending to 200–500°C are based on solid solutions involving BaTiO_3 and/or $\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$ as end-members. These materials, and selected examples of other compositional families, are presented and compared in the following sections. **Tables 1 and 2 summarise dielectric properties, resistivities and RC time constants.**

2.1 BaTiO_3 -based materials

BaTiO_3 - BiScO_3

The BiScO_3 end-member has a high Curie temperature ($\sim 450^\circ\text{C}$) but can only be prepared at high pressures and temperatures ($\sim 6\text{ GPa}$, $\sim 1100^\circ\text{C}$) [18, 19]. Ogihara et al., Penn State University, demonstrated weakly coupled relaxor behaviour in the binary system $(1-x)\text{BaTiO}_3$ - $x\text{BiScO}_3$ [BT-BS] prepared with 3 mol % excess Bi_2O_3 [20]. The Curie peak at $\sim 130^\circ\text{C}$ became diffuse as the BiScO_3 content increased to $x = 0.02\text{BS}$. At $x = 0.05\text{BS}$ an additional, frequency dependent peak appeared at lower temperatures. These dielectric properties were associated with a core-shell microstructure: the shell regions of the grains were enriched in BiScO_3 and were considered to be responsible for the lower temperature frequency dependent dielectric anomaly. A single, very diffuse relaxor ϵ_r -T response occurred for compositions around $x = 0.2\text{BS}$: this gave rise to near-stable ϵ_r values, 800–1000 over a wide temperature range [20]. Similar behaviour had previously been observed in thin film samples [21]. For $x = 0.3$ bulk ceramics, values of $\epsilon_r \sim 1000$ were recorded from temperatures of 0 to 300°C , with high electrical resistivity, $\sim 10^{12}\ \Omega\text{ cm}$ at 250°C . The energy density of pellets and tape-cast thick films of these $x = 0.3$ samples was investigated: a $15\ \mu\text{m}$ dielectric layer had a room-temperature energy density of 6.1 J/cm^3 at a dc bias field of 730 kV/cm , just below the breakdown field. Stable energy densities of 2.3 J/cm^3 for composition $x = 0.3$ were observed for temperatures up to 300°C (at bias fields ~ 30 – 40 kV/cm) [20].

BaTiO_3 - $\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$

The solid solution between BaTiO_3 and $\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$, $[(1-x)\text{BT}-x\text{BMT}]$ has been studied by a number of research groups. Wada et al. focussed on the system’s piezoelectric properties, but noted a changeover from ferroelectric to relaxor characteristics occurred at 0.1

BMT [22]. A plot of ϵ_r -T at 1 MHz showed a very diffuse dielectric response for compositions 0.2BMT and 0.3BMT, with ϵ_r -values of 600-1000 at temperatures from approximately 25 to 400°C. Dielectric loss tangent at 100 Hz was in the range 0.05-0.1.

Zhang et al., provided a detailed account of the temperature stability of dielectric properties [23]. Compositions $x = 0.5$ BMT and 0.6BMT displayed a plateau in ϵ_r -T response: for $x = 0.5$, values of $\epsilon_r \sim 2400 \pm 15 \%$ (1 kHz) were observed for temperatures 167 to 400°C, with $\tan\delta < 0.02$ (100 kHz) for temperatures 238-400°C. For $x = 0.4$, $\epsilon_r \sim 2200 \pm 15 \%$ at temperatures of 175 to 400°C; low losses occurred over most of this temperature range, with $\tan\delta \leq 0.02$ from 197-400°C (at 100 kHz).

A plot of ϵ_r -T for the (1-x)BT-xBMT composition $x = 0.5$ BMT fabricated in our laboratory is shown in Figure 3, values of $\epsilon_{r \text{ mid}} = 2100 \pm 15 \%$ extended from 150-400°C, in general agreement with literature data [23], but ϵ_r is slightly lower than published values, possibly due to differences in ceramic density. Values of $\tan\delta$ were ≤ 0.02 (100 KHz) from 270 to 550°C, and ≤ 0.02 at 1 kHz for the narrow temperatures range 230-300°C.

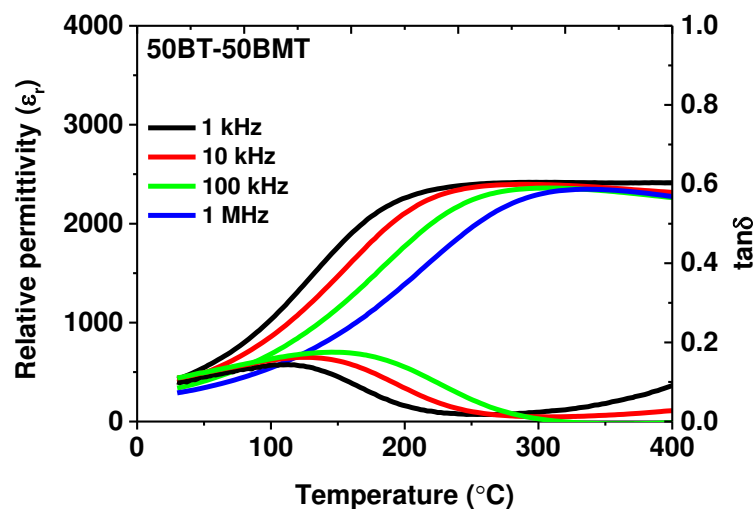


Figure 3. Relative permittivity, ϵ_r , and $\tan\delta$ plot for (1-x)BaTiO₃-xBi(Mg_{0.5}Ti_{0.5})O₃: $x = 0.5$ fabricated in our laboratory after Ref 23.

Choi et al., investigated (1-x)BT-xBMT bulk ceramics and multilayer capacitors (20×129 μm layers) [24]. They found the solubility limit of BMT to occur around $x = 0.4$ -0.5. Highly diffuse relaxor-like behaviour was observed for compositions $x = 0.1$ to 0.4. Different compositions displayed distinctive temperature ranges of stable ϵ_r values, depending on the T_m for each specific composition, however temperature ranges over which ϵ_r varied within $\pm 15 \%$ were not commented upon in detail.

Xiong et al., examined the effect of Nb₂O₅ and Co₂O₃ co-dopants on the properties of (1-x)BT-xBMT: similar dopants are incorporated into BT to develop core-shell structures and X7R temperature-stable performance [25-27]. These authors reported that compositions $x = 0.15$ BMT doped with 2 wt % Nb₂O₅ produced an $\epsilon_r \sim 1000 \pm 15 \%$ over the temperature range -55 to +155°C: $\tan\delta = 0.09$ at room temperature. Microstructures were presented to investigate possible core-shell characteristics.

Ba_{0.8}Ca_{0.2}TiO₃-Bi(Mg_{0.5}Ti_{0.5})O₃

The beneficial effect of Ca-modified BaTiO₃ in solid solution with Bi(Mg_{0.5}Ti_{0.5})O₃ was highlighted at the University of Leeds by Zeb and Milne [16]. Incorporation of Ca²⁺ into BaTiO₃ extends the temperature range of the tetragonal perovskite phase [28]. Some of the best high temperature dielectrics with low dielectric losses over wide temperature ranges are found in this system, Figure 4a. The initial report of (1-x)Ba_{0.8}Ca_{0.2}TiO₃-xBi(Mg_{0.5}Ti_{0.5})O₃ indicated $\epsilon_r = 800 \pm 10\%$ from 45–550°C, with $\tan\delta \leq 0.025$ over the temperature range 100–430°C for x = 0.5BMT [16]. For a slightly higher BMT content, x = 0.55BMT the dielectric properties were superior to 0.5BMT, with $\epsilon_{r \text{ mid}} = 1000 \pm 15\%$ from 80 to 500°C and $\tan\delta \leq 0.02$ from 160–500°C, Figure 4a [17, 29]. Expressing temperature stability as TC ϵ_r , the optimum BCT-BMT compositions exhibit TC ϵ_r of ~ 200 ppm/°C (where $TC\epsilon_r = 1/\epsilon_{r \text{ mid}}[(\epsilon_{r1} - \epsilon_{r2})/(T_1 - T_2)]$). The materials with optimum dielectric properties have high resistivity: ~10¹⁰ Ω m at 250°C and 10⁷ Ω m at 400°C.

Increasing the BMT content to x = 0.6 resulted in a minor second phase in XRD patterns, attributed to bismuth titanate. There was also a decrease in resistivity to 10⁸ Ω m at 250°C and 10⁶ Ω m at 400°C, giving higher apparent values of $\epsilon_{r \text{ mid}} = 2100 \pm 10\%$ - in the temperature range of 140–420°C: $\tan\delta \leq 0.025$ from 170 to 300°C, Figure 4b [16]. The changeover in properties and increased conductivity at x = 0.6 is thought to be linked to a different defect structure relative to x ≤ 0.55 compositions.

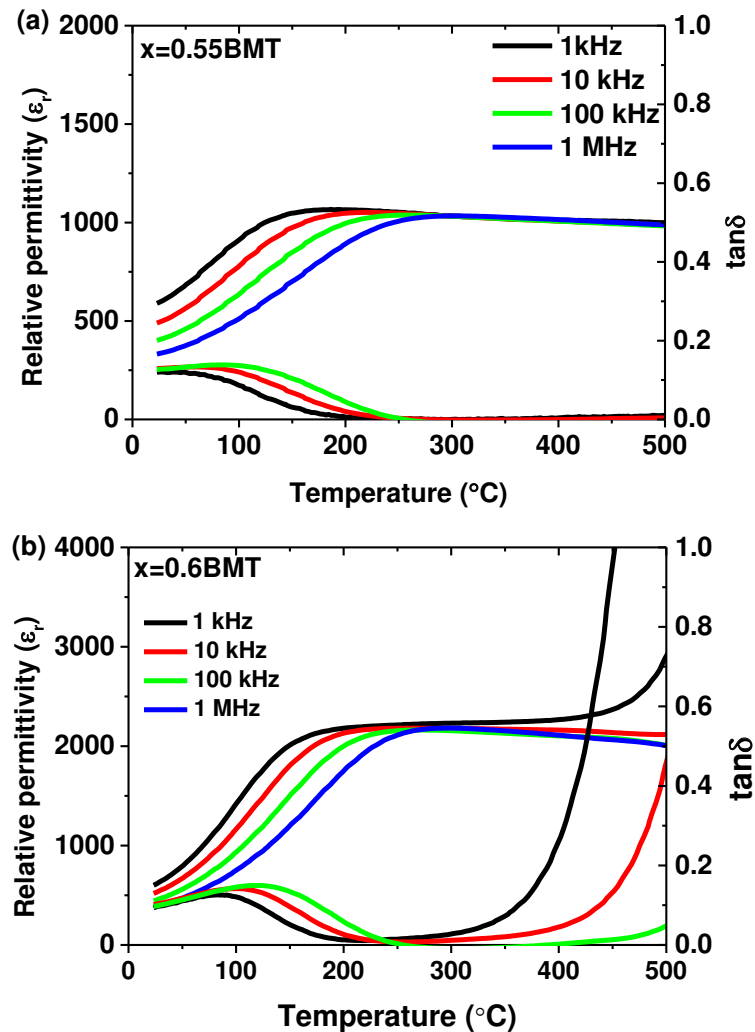


Figure 4. Relative permittivity ϵ_r and $\tan\delta$ versus temperature for (1-x)BCT-xBMT system at (a) x = 0.55, and (b) x = 0.6 [16].

A similar temperature stable dielectric response, but over a narrower temperature range to the optimum $\text{Ba}_{0.8}\text{Ca}_{0.2}\text{TiO}_3\text{-Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$ samples, was reported for Ca and Zr co-modified compositions. The incorporation of 15 mole% Ca^{2+} allied to 10 mol % Zr substitution, in the solid solution series, $(1-x)\text{Ba}_{0.85}\text{Ca}_{0.15}\text{Zr}_{0.1}\text{Ti}_{0.9}\text{O}_3\text{-}x\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$, resulted in $\epsilon_{r \text{ mid}} \sim 1200$ from 100 to 350°C, with $\tan \delta \leq 0.025$ from 150°C to 350°C for $x = 0.5$ and 0.6 (estimated from published plots) [30]. The corresponding $\epsilon_r\text{-}T$ plot for a $(1-x)\text{Ba}_{0.85}\text{Ca}_{0.15}\text{Zr}_{0.1}\text{Ti}_{0.9}\text{O}_3\text{-}x\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$ ceramic of composition $x = 0.6$ prepared in our laboratory is shown in Figure 5: $\epsilon_{r \text{ mid}} \sim 1100 \pm 15\%$ from 70 to 500°C, with $\tan \delta \leq 0.02$ from 125°C to 480°C.

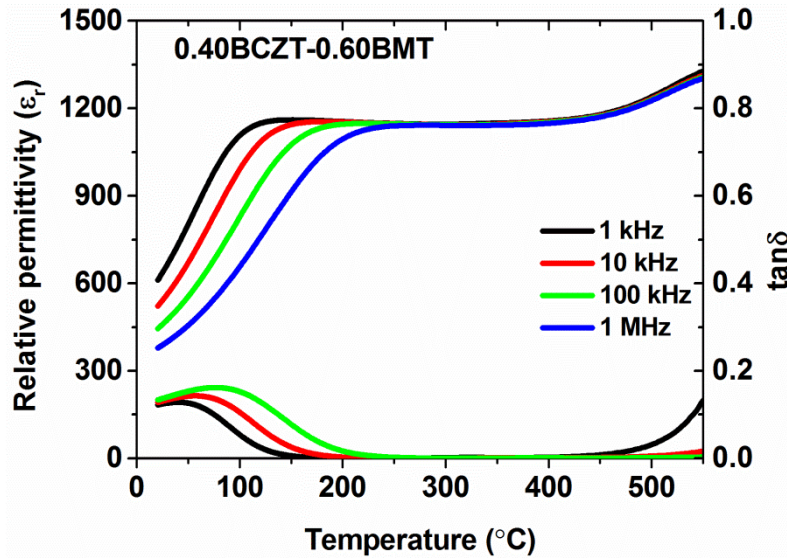


Figure 5. Relative permittivity, ϵ_r , and $\tan \delta$ plot for $0.4\text{Ba}_{0.85}\text{Ca}_{0.15}\text{Zr}_{0.1}\text{Ti}_{0.9}\text{O}_3\text{-}0.6\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$ fabricated in our laboratory after Ref 30.

$\text{Ba}_{0.6}\text{Sr}_{0.4}\text{Zr}_{0.2}\text{Ti}_{0.8}\text{O}_3\text{-BiMg}_{0.5}\text{Ti}_{0.5}\text{TiO}_3$

Temperature-stable relative permittivity varying by no more than 15% over wide temperature ranges was observed for $(1-x)\text{Ba}_{0.6}\text{Sr}_{0.4}\text{Zr}_{0.2}\text{Ti}_{0.8}\text{O}_3\text{-}x\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{TiO}_3$ ceramics. Composition $x = 0.2$ gave $\epsilon_{r \text{ mid}} = 500 \pm 15\%$ from -70 to 300°C, with $\tan \delta < 0.02$ from -60 to 300°C [31]. This matches the target -55 to 300°C specification in terms of both stable ϵ_r and low dielectric loss.

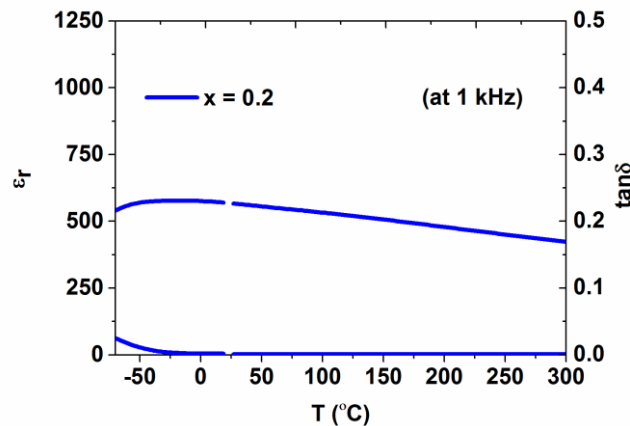


Figure 6 Relative permittivity ϵ_r and $\tan\delta$ plots for $(1-x)\text{Ba}_{0.6}\text{Sr}_{0.4}\text{Zr}_{0.2}\text{Ti}_{0.8}\text{O}_3$ - $x\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{TiO}_3$ $x = 0.2$. [31]

$\text{Ba}_{0.8}\text{Ca}_{0.2}\text{TiO}_3$ - $\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$ - NaNbO_3

A study of $0.45\text{Ba}_{0.8}\text{Ca}_{0.2}\text{TiO}_3$ -($0.55-x$) $[\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$ - $x\text{NaNbO}_3]$ ceramic compositions ($x = 0$ to 0.3) led to a material in which the lower limit of $\pm 15\%$ stability in ϵ_r was shifted to sub-zero temperatures, as compared to the parent BCT-BMT system [16, 17, 29]. Incorporation of NaNbO_3 at $x = 0.2$ decreased T_m to 0°C , from 160°C in the unmodified material, Figure 7. The composition $x = 0.2$ gave $\epsilon_{r \text{ mid}} = 600 \pm 15\%$ in the temperature range -70°C to 500°C , and $\tan\delta \leq 0.02$ from -20 to 400°C . Further incorporation of NaNbO_3 to $x = 0.3$ in the solid solution decreased T_m to -55°C with $\epsilon_{r \text{ mid}} = 550 \pm 15\%$ in the temperature range -70°C to 300°C , and $\tan\delta \leq 0.02$ from -60 to 300°C , again meeting the desire for stability to -55°C , but at the expense of decreases in ϵ_r . Values of dc resistivity were in the range $\sim 10^{10} \Omega \text{ m}$ at 250°C and $\sim 10^7 \Omega \text{ m}$ at 400°C with RC time constant 3-4s (300°C).

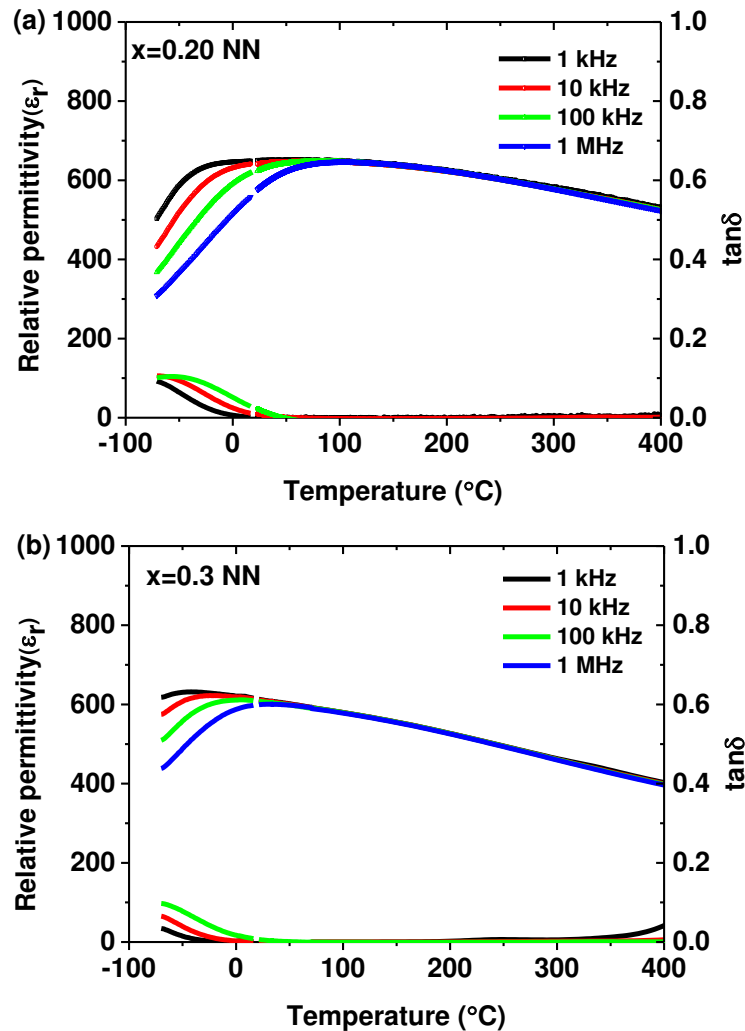


Figure 7. Relative permittivity ϵ_r and $\tan\delta$ for $0.45\text{Ba}_{0.8}\text{Ca}_{0.2}\text{TiO}_3$ -($0.55-x$) $\text{Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$ - $x\text{NaNbO}_3$, (a) $x = 0.2$, and (b) $x = 0.3$ [17,29]

BaTiO₃-Bi(Zn_{0.5}Ti_{0.5})O₃

The (1-x)BaTiO₃-xBi(Zn_{0.5}Ti_{0.5})O₃ system, BT-BZT, was studied by Huang and Cann at Oregon State University, who determined the solid solution limit to occur at $x = 0.33$ BZT [32]. The crystal system changed from tetragonal for $x < 0.1$ to mixed tetragonal and rhombohedral at $x \sim 0.1$. The ferroelectric Curie peak became broad at $x = 0.05$, T_c decreased relative to BT, and the lower temperature ϵ_r discontinuities due to tetragonal-orthorhombic-rhombohedral polymorphic phase transitions disappeared. Further increases in the BZT content caused dielectric peaks to become increasingly diffuse, and relaxor behaviour was reported at $x = 0.2$ BZT.

A subsequent study by Raengthon and Cann investigated the effect of introducing Ba vacancies (2 mol%-8 mol%) into 0.8BT-0.2BZT ceramics [33]. Composition with 2 mole% Ba-deficiency were summarised to give improved temperature stability of ϵ_r , with a nearly flat response from temperatures of 100°C to 350°C. Designing compositions with Ba vacancies also increased electrical resistivity: the optimum $x = 0.2$ BZT composition (2 mol % Ba deficient) resistivity was of the order of $\sim 7 \times 10^{10} \Omega \text{ cm}$ at 270°C, decreasing to $5.78 \times 10^9 \Omega \text{ cm}$ at 335°C and with a RC time constant of 1.47 s (335°C). The same research group have proceeded to further characterise BT-BZT ceramics. Incorporating Zr and Mn excess into the BT-BZT based system gave no significant improvements in temperature stability [33]. The group also reported the (1-x)[0.5BaTiO₃-0.5Bi(Zn_{0.5}Ti_{0.5})O₃]-xK_{0.5}Bi_{0.5}TiO₃ system: a relatively stable dielectric response was found for composition $x = 0.6$ KBT. Approximate values (estimated by interpolation of published diagrams) were $\epsilon_{r \text{ mid}} \sim 2400 \pm 15\%$ in the temperature range from 150 to 450°C with $\tan \delta \sim 0.02$ from 200-350°C [34]. Hao et al. have explored core shell structures in doped BT-BZT ceramics fabricated using powders produced by precipitation and by sol-gel methods [35].

BaTiO₃-Bi(Zn_{1/2}Ti_{1/2})O₃-BiInO₃

A dielectric study of the (1-x)[0.5Bi(Zn_{1/2}Ti_{1/2})O₃-0.5BiInO₃]-xBaTiO₃ ceramic system conducted by Raengthon and Cann revealed a broad and temperature stable dielectric response for compositions $x = 0.75$ and 0.8 [36]. The estimated values interpolated from published plots for composition $x = 0.75$ were, $\epsilon_{r \text{ mid}} \sim 1050 \pm 15\%$ from 20°C to 500°C with $\tan \delta \leq 0.05$ from 50 to 390°C. Incorporation of Ba-vacancies (2 mol %) led to decrease of $\tan \delta$ from 0.184 to 0.008 at 400°C.

BaTiO₃-BiZn_{0.5}Ti_{0.5}O₃-BiScO₃

The incorporation of BiScO₃ into the BT-BZT system further flattens the $\epsilon_r(T)$ response [37]. The solid solution composition, 50BaTiO₃-25Bi(Zn_{0.5}Ti_{0.5})O₃-25BiScO₃, compositionally engineered to have 2 mole% Ba-deficiency exhibited $\epsilon_r \sim 1100$ from 80 to 500°C (estimated from published plot) with a temperature coefficient of permittivity $TC\epsilon_r = -182 \text{ ppm/}^\circ\text{C}$ [37], which corresponds to 5% variation (estimated). Dielectric losses were low, with $\tan \delta = 0.007$ at 335°C. An example of the properties of 50BaTiO₃-25Bi(Zn_{0.5}Ti_{0.5})O₃-25BiScO ceramic (with 2 mol % Ba deficiency) fabricated in our laboratory is shown in Figure 8. This material, along with BCT-BMT, $x \sim 0.5$, developed later in Leeds (Figure 4a), exhibits the widest temperature ranges of stable ϵ_r and low $\tan \delta$ of any material being considered as a high temperature, high permittivity dielectric. However a disadvantage of this material lies in the very high costs of Sc₂O₃. Electrical resistivity reported by Raengthon et al., was $4.1 \times 10^9 \Omega \text{ cm}$ at 335°C, higher than for BCT-BMT ceramics.

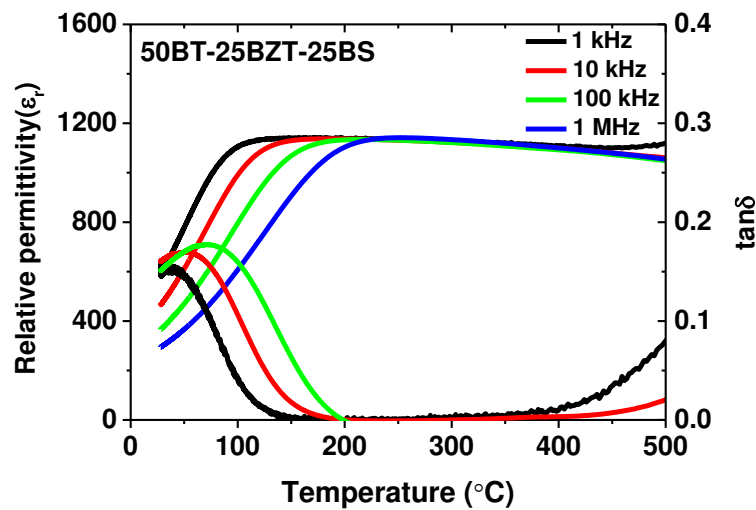


Figure 8 Relative permittivity ϵ_r and $\tan\delta$ versus temperature for 50BaTiO₃-25Bi(Zn_{0.5}Ti_{0.5})O₃-25BiScO ceramic with 2 mol % Ba deficiency (fabricated in our laboratory after Ref 37).

BaTiO₃-Bi(Zn_{0.5}Ti_{0.5})O₃-NaNbO₃

Raengthon et al., found that incorporation of small amounts of NaNbO₃ into BaTiO₃-Bi(Zn_{0.5}Ti_{0.5})O₃ (BT-BZT) according to a compositional formula expressed in mol% terms as, 70BaTiO₃-(30-y)Bi(Zn_{0.5}Ti_{0.5})O₃-yNaNbO₃, y = 5-25 shifted T_m to lower temperatures, thereby decreasing the lower temperature limit of stable ϵ_r to -103°C from a value of ~100 °C without NaNbO₃ modification [32, 38]. Dielectric properties (ϵ_r -T plots) were shown from -150 °C to + 200 °C: a number of NaNbO₃ modified compositions e.g. 70BaTiO₃-5Bi(Zn_{0.5}Ti_{0.5})O₃-25NaNbO₃ displayed a temperature range of stable ϵ_r better than X9R (-55-175°C). The average ϵ_r values fell from ~ 1500 in BT-BZT to ≤ 700 for the NaNbO₃ modified compositions with the best low-temperature performance.

Ba_{0.8}Ca_{0.2}TiO₃-Bi(Zn_{0.5}Ti_{0.5})O₃

Zeb and Milne investigated the dielectric and ferroelectric properties of (1-x)Ba_{0.8}Ca_{0.2}TiO₃-xBi(Zn_{0.5}Ti_{0.5})O₃: a nearly flat dielectric response was obtained for x = 0.3 with relative permittivity, $\epsilon_r = 1030 \pm 15$ % over temperatures from $\leq 25^\circ\text{C}$ to 425°C, with $\tan\delta \leq 0.025$ in the temperature range 85-460°C [39]. The dc resistivity was $10^9 \Omega \text{ m}$ at a temperature of 300°C for x = 0.3, Figure 9.

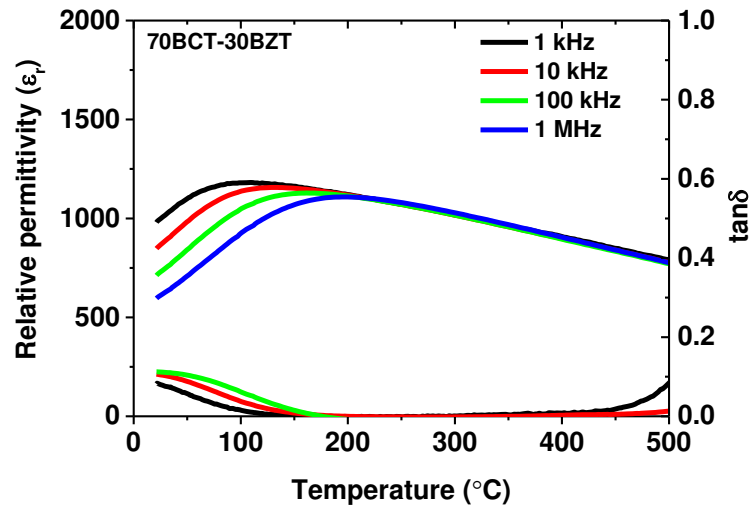


Figure 9. Relative permittivity ϵ_r and $\tan\delta$ plot for $(1-x)\text{Ba}_{0.8}\text{Ca}_{0.2}\text{TiO}_3\text{-}x\text{Bi}(\text{Zn}_{0.5}\text{Ti}_{0.5})\text{O}_3$: $x = 0.3$ [39]

BaTiO₃-Bi(Zn_{0.5}Zr_{0.5})O₃

The dielectric properties of $(1-x)\text{BaTiO}_3\text{-}x\text{Bi}(\text{Zn}_{0.5}\text{Zr}_{0.5})\text{O}_3$ [BT- $x\text{BZZ}$] were studied by Wang et al.,[40]. Increasing the BZZ content induced relaxor behaviour in ϵ_r -T plots, with suppressed values of $\epsilon_{r\text{ max}}$. Good temperature stability in ϵ_r was reported for $x = 0.6$, with $\epsilon_{r\text{ mid}} = 1000 \pm 15\%$ from 200 to 450 °C, with $\tan\delta \leq 0.25$ from room temperature to 300 °C (estimated).

BaTiO₃-Bi(Mg_{0.5}Zr_{0.5})O₃

Zeb and Milne demonstrated stability in relative permittivity in the ceramic system $(1-x)\text{BaTiO}_3\text{-}x\text{Bi}(\text{Mg}_{0.5}\text{Zr}_{0.5})\text{O}_3$, BT- $x\text{BMZ}$ [41]. The end member BT ($x = 0$) changed from tetragonal to pseudocubic phase at $x \geq 0.1\text{BMZ}$; a single phase solid solution was obtained for $x < 0.5\text{BMZ}$. The $x = 0.03$ and 0.05BMZ compositions exhibited double peaks in ϵ_r -T plots which correlated to core-shell grain structures, as confirmed by TEM analysis. However composition $x = 0.3\text{BMZ}$ gave a stable dielectric response, with $\epsilon_{r\text{ mid}} = 570 \pm 15\%$ from -20°C to 430°C, and $\tan\delta \leq 0.02$ from 30-420°C, Figure 10. Composition $x = 0.4\text{BMZ}$ gave $\epsilon_{r\text{ mid}} = 600 \pm 15\%$ from 25°C to 420°C with $\tan\delta \leq 0.02$ from 55°C to 280°C, Figure 10. Values of dc resistivity were $10^9 \Omega\text{ m}$ at 250°C, and $10^6 \Omega\text{ m}$ at 400°C.

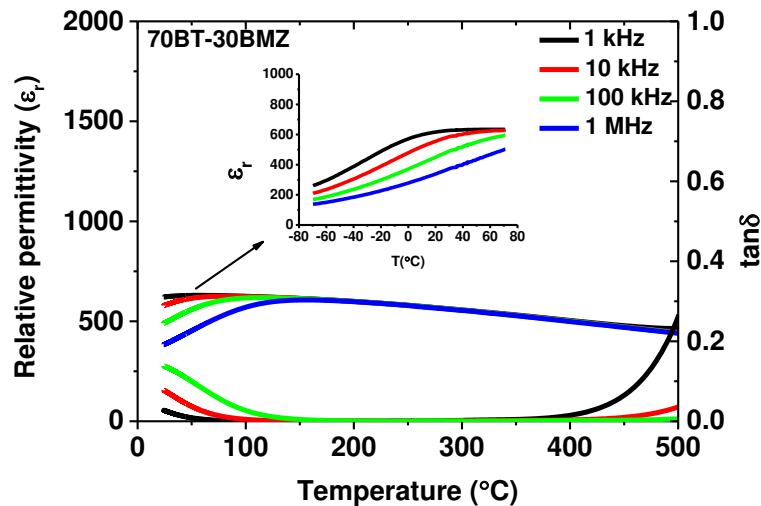


Figure 10. Relative permittivity, ϵ_r , and $\tan\delta$ plot for $(1-x)\text{BaTiO}_3\text{-}x\text{Bi}(\text{Mg}_{0.5}\text{Zr}_{0.5})\text{O}_3$: $x = 0.3$ (inset shows ϵ_r from temperature -70 to $+70$ °C) [41].

BaTiO₃-Bi(Mg_{2/3}Nb_{1/3})O₃

Wang et al., examined the solid solution, $(1-x)\text{BaTiO}_3\text{-}x\text{Bi}(\text{Mg}_{2/3}\text{Nb}_{1/3})\text{O}_3$, reporting basic dielectric properties and energy storage capabilities [42]. Composition $x = 0.2$ exhibited temperature-stable dielectric response with ϵ_r varying from 628–787 in the temperature range -50 to $+300^\circ\text{C}$: $\tan\delta \leq 0.025$ over the temperature range $0\text{--}150^\circ\text{C}$ (estimated). Values of dc resistivity were of $7.4 \times 10^{12} \Omega \text{ cm}$ at room temperature and energy density of 0.74 J/cm^3 (160 kV/cm) was recorded for $x = 0.2$. However, all compositions of this system showed a sharp increase in dielectric loss tangent at temperature $\geq 200^\circ\text{C}$.

BaTiO₃-Bi(Mg_{2/3}Ta_{1/3})O₃

Ma et al., studied the dielectric properties of the $(1-x)\text{BaTiO}_3\text{-}x\text{Bi}(\text{Mg}_{2/3}\text{Ta}_{1/3})\text{O}_3$ ceramic system [43]. Composition $x = 0.1$ exhibited dielectric stability across the temperature range 30 to 150°C , with $\epsilon_{r \text{ max}} = 1278$: $\tan\delta \leq 0.02$ over the temperature range 30°C to 195°C . There was a sharp rise in dielectric loss tangent at a temperature of $\geq 200^\circ\text{C}$.

BaTiO₃-BiAlO₃

Liu et al., fabricated the binary $(1-x)\text{BaTiO}_3\text{-}x\text{BiAlO}_3$ ceramic system by solid state and sol-gel processing routes [44]. The temperature stability in $\epsilon_r\text{-}T$ plots increased with increases in the BiAlO_3 content. The best temperature stability in ϵ_r was demonstrated for ceramic samples fabricated using powders prepared by the sol-gel method. At $x = 0.3\text{BiAlO}_3$, $\epsilon_{r \text{ max}} = 660 \pm 15\%$ over the temperature range -55 to 440°C : $\tan\delta \sim 0.012$ at room temperature. However, conventional solid state methods for producing the starting powders failed to achieve this level of temperature range of stability. The reported relative permittivity for the solid state route for composition $x = 0.3$ was $\epsilon_r = 1558 \pm 15\%$ across the temperature range, -55 to 124°C . These researchers also studied the effect of Nb incorporation to $0.8\text{BaTiO}_3\text{-}0.2\text{BiAlO}_3$ ($x = 0.2$) to try to extend the working temperature range. A sample composition containing 4 mol\% Nb displayed $\epsilon_r = 925 \pm 15\%$ from -55 to 178°C , and $\tan\delta \sim 0.004$ in the temperature range -20 to 200°C (estimated).

A summary of properties of selected BaTiO_3 and $\text{Bi}_{0.5}\text{Na}_{0.5}\text{TiO}_3$ based materials is presented in Table 2.

2.2 Na_{0.5}Bi_{0.5}TiO₃-based materials

Na_{0.5}Bi_{0.5}TiO₃-NaNbO₃

The system $(1-x)\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-}x\text{NaNbO}_3$ (NBT-NN) was investigated for NaNbO_3 contents up to $x = 0.08$ [45]. The NBT end-member is a relaxor dielectric with a broad ϵ_r peak at $\sim 300^\circ\text{C}$, and shoulder at $\sim 180^\circ\text{C}$. Incorporation of NaNbO_3 in the range $x = 0.01\text{--}0.03$ shifts the peak and shoulder to lower temperatures; both features become increasingly diffuse for NaNbO_3 modified samples [45]. At $x = 0.08$, a broad $\epsilon_r(T)$ plateau extends from $\sim 200\text{--}400^\circ\text{C}$ but with continued evidence of two distinct humps.

Bridger et al., patented a series of high temperature dielectric materials based on the relaxor sodium bismuth titanate (NBT) [46]. A variety of substituents and dopants were used to broaden and adjust the temperature of the $\epsilon_r(T)$ shoulder and main peak. Example

minor substituents included Sr, Ca, Ba: a further flattening of the dielectric response was achieved, along with increases in electrical resistivity, through the use of dopants (Mn, Cu, Co). In agreement with earlier work by Li et al., [45] the binary solid solution between $\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$ and NaNbO_3 displayed a flattened dielectric response over a wide temperature range [46]. Optimum compositions gave $\epsilon_r > 1000$, and $\tan\delta < 0.02$ over the temperature range -30 to $+200^\circ\text{C}$: resistivity was $> 10^{10} \Omega \text{ m}$. The wide variety of compositions described in the 2008 Bridger patent application, with full patent granted in 2010, can be grouped into two categories depending on the temperature range of stable dielectric response: (a) compositions with stable properties from $< 0^\circ\text{C}$ to $+200^\circ\text{C}$; (b) higher temperature dielectrics with stability from a minimum temperature $200^\circ\text{C} \pm 100^\circ\text{C}$ to an upper limit $400^\circ\text{C} \pm 100^\circ\text{C}$. Certain dopants increased resistivity and improved voltage coefficients to within $\pm 20\%$ (or in some cases $\pm 10\%$) for electric fields up to 10 MV/m [46, 47]. Specific examples of the main NBT parent compositions reported by Bridger et al., and their dielectric properties are presented in summary Table 2.

$\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-KTaO}_3$

König et al., reported trends in $\epsilon_r(T)$ peak temperatures and widths of ϵ_r peaks of various $(1-x)\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-}x\text{KTaO}_3$ binary compositions [48]. Increasing the KTaO_3 content resulted in a flatter $\epsilon_r\text{-}T$ response: for composition $x = 0.2$, $\epsilon_{r \text{ mid}} = 2000 \pm 15\%$, in the temperature range $80\text{--}300^\circ\text{C}$ (estimated) with $\tan\delta \leq 0.02$ over a narrower temperature range, from 200 to 300°C . For composition $x = 0.05$ annealed at high temperatures, a broad dielectric maxima $\epsilon_{r \text{ max}} = 2700$, from 160 to 260°C with $\tan\delta \leq 0.02$ was reported spanning temperatures from 100 to 300°C (estimated).

$\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-BaTiO}_3\text{-K}_{0.5}\text{Na}_{0.5}\text{NbO}_3$

Dittmer et al., Technical University Darmstadt, studied the ternary system, $(1-x)(0.94\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-}0.06\text{BaTiO}_3)\text{-}x\text{K}_{0.5}\text{Na}_{0.5}\text{NbO}_3$, [NBT-BT-KNN] for compositions $x \leq 0.18$ KNN [49]. In a similar manner to NBT-based materials reported by Li et al., for the $\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-NaNbO}_3$ system, and by Bridger et al., for complex compositions based on NBT [45, 46]. Dittmer et al., observed a $\epsilon_r(T)$ plateau which exhibited two broad humps originating from the shoulder and broad ϵ_r peak in the base material. However the width of the $\epsilon_r\text{-}T$ plateau was greater in the NBT-BT-KNN system. Optimum properties occurred at $x = 0.18$ KNN, with $\epsilon_r = 2151 \pm 10\%$, from temperatures of 43°C to 319°C : $\tan\delta \leq 0.025$ from ~ 50 to $< 300^\circ\text{C}$ (estimated from published plot). For NBT-BT-KNN at $x = 0.18$, electrical resistivity was $10^8 \Omega \text{ m}$ at 300°C , and RC time constant $\sim 1.13 \text{ s}$. For $x = 0.15$, the reported properties were, $\epsilon_{r150} = 2349 \pm 10\%$ from 49 to 313°C , with $\tan\delta \leq 0.025$ from $\sim 100\text{--}300^\circ\text{C}$ (estimated).

$\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-K}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-K}_{0.5}\text{Na}_{0.5}\text{NbO}_3$

The Darmstadt group subsequently studied $(1-x)[0.6\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-}0.4\text{K}_{0.5}\text{Bi}_{0.5}\text{TiO}_3]\text{-}x\text{K}_{0.5}\text{Na}_{0.5}\text{NbO}_3$, $x = 0.08\text{--}0.015$ ceramics, reporting $\epsilon_r = 2167 \pm 10\%$, from 54 to 400°C for the best composition, $x = 0.15$ KNN. In compositions with the widest temperature range of stability in ϵ_r , namely $x = 0.12$ and 0.15 KNN, $\tan\delta < 0.025$ (1 kHz) over what appeared to be a temperature span, $\sim 100\text{--}250^\circ\text{C}$ (estimated) compared to ϵ_r stability over a broader temperature range, 54 to 400°C [50].

There is some evidence from published data that dielectric losses in NBT-KBT-KNN show a greater temperature fluctuation than for the leading $\text{BaTiO}_3\text{-Bi}(\text{Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$ or $\text{BaTiO}_3\text{-Bi}(\text{Zn}_{0.5}\text{Ti}_{0.5})\text{O}_3$ based dielectric ceramics, and in NBT-KBT-KNN low loss occurs over a significantly narrower temperature range than the full range of the ϵ_r plateau. However a full comparison of ceramics of the different leading systems prepared on one laboratory

would be required to verify this observation and to confirm working temperature ranges in terms of ϵ_r stability and low loss.

The effect of incorporating CaZrO_3 into NBT-BT and NBT-BT-KNN was to decrease the lower operating temperature and also to decrease ϵ_r values [51, 52]. The materials were prepared according to solid solution formulae: $(1-x)[0.94\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3-0.06\text{BaTiO}_3]-x\text{CaZrO}_3$ and $(1-x)[0.82(0.94\text{Na}_{0.5}\text{Bi}_{0.5}\text{TiO}_3-0.06\text{BaTiO}_3)-0.18\text{K}_{0.5}\text{Na}_{0.5}\text{NbO}_3]-x\text{CaZrO}_3$ respectively. Ceramics with different CaZrO_3 [CZ] contents exhibited different combinations of $\epsilon_{r\text{ max}}$ and plateau temperature ranges. For the NBT-BT-CZ compositional series, the lower limiting temperature of near flat $\epsilon_r(T)$ decreased with increasing amounts of CaZrO_3 substitution, from 109°C at 0.05CZ to -97°C at 0.2CZ. For NBT-BT-KNN-CZ solid solutions, the variation was from -6°C to -69°C with increasing levels of CaZrO_3 incorporation. Dielectric losses (1 kHz) increased sharply at temperatures above 200-300°C in both NBT-BT-CZ and NBT-BT-KNN-CZ. The NBT-BT-CZ composition $x = 0.2\text{CaZrO}_3$ gave the flattest ϵ_r -T response, with a $\pm 15\%$ consistency in ϵ_r (550 mean) from -97 to +371°C, with $\tan\delta = 0.7\%$ at 300°C (1 kHz). Dielectric losses (deduced from ϵ'' -T plots) increased substantially above 300°C, suggesting a practical upper working temperature (combination of stable ϵ_r and low loss) may be $\sim 300^\circ\text{C}$.

In the NBT-BT-KNN-CZ system, the flattest ϵ_r -T response again occurred for $x = 0.2\text{CZ}$ [51]. In this case, the temperature range of $\pm 15\%$ consistency in ϵ_r (467 mean) extended from -69°C to + 468°C; dielectric loss at 1 kHz ($\tan\delta = \epsilon''/\epsilon_r'$) increased sharply above 300°C. An electrical resistivity of $\sim 10^7 \Omega \text{ m}$ at 300°C was recorded for the BNT-BT-CZ composition $x = 0.2$ which had the most stable dielectric properties. For the BNT-BT-KNN-CZ compositions, the electrical resistivity was $\sim 10^8 \Omega \text{ m}$ at 300°C for $x = 0.2\text{CZ}$; other compositions with less favourable ϵ_r -T response exhibited higher resistivity, up to $10^9 \Omega \text{ m}$ (e.g. BNT-BT-KNN-0.05 CZ).

$\text{Bi}_{0.5}\text{Na}_{0.5}\text{TiO}_3$ - BaTiO_3 - $\text{Bi}_{0.2}\text{Sr}_{0.7}\text{TiO}_3$

Shi et al., reported the electrical properties for the Bi-deficient solid solution series ' $(\text{Bi}_{0.5-y}\text{Na}_{0.5})_{0.94-x}\text{Ba}_{0.06}(\text{Bi}_{0.2}\text{Sr}_{0.7}\square_{0.1})_x\text{TiO}_3$ ' derived from a BNT-BT composition at its morphotropic phase boundary [53]. The system demonstrated promising temperature stable dielectric properties with low loss tangent. A flat dielectric response with very high relative permittivity, $\epsilon_r = 4884 \pm 10\%$ was reported for composition $x = 0.26$, $y = 0.07$ over the temperature span 50°C to 270°C: $\tan\delta \leq 0.02$ from 100 to 300°C (estimated). A rapid decrease in ϵ_r occurred for temperatures outside this range. The value of time constant (RC) was 5.96 s at a temperature of 300°C.

Table 2 Summary of selected perovskites high temperature dielectrics with wide temperature ranges of stable relative permittivity (within $\pm 15\%$)

Material system	ϵ_r mid (T range, °C)	T range (°C) $\tan\delta \leq 0.02$ (1 kHz)	ρ (Ω m) at T (°C)	RC (s) at T(°C)
0.7BaTiO ₃ -0.3BiScO ₃ [20]	1000 \pm 15%(0-300)	50-400	-	-
0.5BaTiO ₃ -0.5Bi(Mg _{0.5} Ti _{0.5})O ₃ [23]	2400 \pm 15%(167-400)	238-400 (100 kHz)	-	-
0.5Ba _{0.8} Ca _{0.2} TiO ₃ - 0.5Bi(Mg _{0.5} Ti _{0.5})O ₃ [16]	800 \pm 10%(45-550)	(100-400)	1.6 \times 10 ⁹ (300°C)	14.8 (300 °C)
0.45Ba _{0.8} Ca _{0.2} TiO ₃ - 0.55Bi(Mg _{0.5} Ti _{0.5})O ₃ [17]	950 \pm 15%(70-600)	160-550	10 ⁹ (300°C)	10.4 (300 °C)
0.8BaTiO ₃ -0.2Bi(Zn _{0.5} Ti _{0.5})O ₃ (Ba-deficient [33])	1150 \pm 15%(100-350)	$\tan\delta \sim 0.05$ (100-460)	5.78 \times 10 ⁷ (335°C)	1.47 (335°C)
0.7Ba _{0.8} Ca _{0.2} TiO ₃ - 0.3Bi(Zn _{0.5} Ti _{0.5})O ₃ [39]	1030 \pm 15%(25-425)	85-460	10 ⁸ (300°C)	-
0.5BaTiO ₃ -0.25BZT-0.25BS (Ba- deficient) [37]	1100 \pm 15%(80-500)	\sim 100-450	4.1 \times 10 ⁷ (335°C)	0.44 (335°C)
0.45Ba _{0.8} Ca _{0.2} TiO ₃ - 0.35Bi(Mg _{0.5} Ti _{0.5})O ₃ -0.2NaNbO ₃ [17]	600 \pm 15%(-70-+500)	-20-400	5.2 \times 10 ⁸ (300°C)	4.00 (300°C)
0.7Na _{0.5} Bi _{0.5} TiO ₃ -0.3NaNbO ₃ [46, 47]	>500 \pm 15%(-80-200)	-80- +150	-	-
0.9Na _{0.5} Bi _{0.5} TiO ₃ -0.1KTaO ₃ [46, 47]	>2500 \pm 15%(80-340)	$\tan\delta \sim 0.05$ (80-300)	-	-
0.82(0.94Na _{0.5} Bi _{0.5} TiO ₃ - 0.06BaTiO ₃)-0.18K _{0.5} Na _{0.5} NbO ₃ [49]	2151 \pm 10%(43-319)	$\tan\delta \leq 0.025$ (50-300)	10 ⁸ (300°C)	1.13 (300°C)
0.85[0.6Na _{0.5} Bi _{0.5} TiO ₃ - 0.4K _{0.5} Bi _{0.5} TiO ₃]- 0.15K _{0.5} Na _{0.5} NbO ₃ [50]	2167 \pm 10%(54-400)	\sim 100-250	\sim 10 ⁵ (300°C)	0.042(300°C)
0.8[0.82(0.94Na _{0.5} Bi _{0.5} TiO ₃ - 0.06BaTiO ₃)-0.18K _{0.5} Na _{0.5} NbO ₃]- 0.2CaZrO ₃ [51]	467 \pm 15%(-69-+468)	-	\sim 10 ⁸ (300°C)	1.07 (300 °C)

2.3 Other Materials

BiScO₃-BaTiO₃-(K_{1/2}Bi_{1/2})TiO₃

Lim et al. investigated the ternary $(1-x)[0.4\text{BiScO}_3\text{-}0.6\text{BaTiO}_3]\text{-}x\text{K}_{0.5}\text{Bi}_{0.5}\text{TiO}_3$ series [54]. The $x = 0.2\text{KBT}$ material displayed a temperature-insensitive response with $\epsilon_{r \text{ max}} = 1750$, and $\text{TC}\epsilon_r = -800 \text{ ppm/}^\circ\text{C}$ across the temperature range $200\text{-}400^\circ\text{C}$: $\tan\delta < 0.02$ for the equivalent temperature range. The energy density increased from 0.3 J/cm^3 at 50 kV/cm to 4.0 J/cm^3 at 220 kV/cm . An electrical resistivity of $10^9 \Omega \text{ cm}$ and RC constant 0.8 s at 300°C were reported.

K_{0.5}Bi_{0.5}TiO₃-BiScO₃

Kruea-In et al. reported temperature-insensitive dielectric properties in the $(1-x)\text{K}_{0.5}\text{Bi}_{0.5}\text{TiO}_3\text{-}x\text{BiScO}_3$, KBT-BS relaxor system [18]. Compositions $x = 0.15\text{BS}$ and $x = 0.2\text{BS}$ presented flat $\epsilon_r\text{-}T$ responses: for example $x = 0.15$ exhibited a $\pm 3\%$ variation in relative permittivity about $\epsilon_{r \text{ mid}} = 2880$ across the temperature range 227°C to 427°C . Independently Martín-Arias et al., reported a similar temperature stable dielectric response for composition $x = 0.2$ [55].

K_{0.5}Na_{0.5}NbO₃-LiTaO₃

Another approach to achieving wide-ranging temperature stability is not reliant on relaxor behaviour. Instead ferroelectrics with high T_c offer stable properties below T_c , albeit with moderate ϵ_r values. This is illustrated by the $(1-x)\text{K}_{0.5}\text{Na}_{0.5}\text{NbO}_3\text{-}x\text{LiTaO}_3$ solid solution series [KNN-LT], taking advantage of the high ferroelectric Curie temperature of NKN ($T_c \sim 420^\circ\text{C}$). Unmodified NKN displays an orthorhombic \leftrightarrow tetragonal polymorphic phase transition at $\sim 200^\circ\text{C}$ creating a ϵ_r discontinuity which prevents temperature stability in ϵ_r values at $T < T_c$. This transition can be shifted to much lower temperatures through appropriate levels of LiTaO₃ incorporation, Figure 11, as demonstrated by Skidmore et al. [56, 57]. The polymorphic phase transition can be shifted to below 0°C by incorporation of between 0.7LT and 0.1LT , thereby imparting improved temperature stability. A flat $\epsilon_r\text{-}T$ response was obtained for $x = 0.1\text{LiTaO}_3$ from temperatures -50°C to 350°C with $\epsilon_r \sim 480 \pm 15\%$: the upper temperature limit lies at the onset of the tail to the ferroelectric Curie peak ($T_c \sim 450^\circ\text{C}$) [56]. For the composition $x = 0.07$, a slightly narrower temperature-stable range occurred, with $\epsilon_r = 630\text{-}700 \pm 15\%$ from -15°C to $+300^\circ\text{C}$ [56, 58].

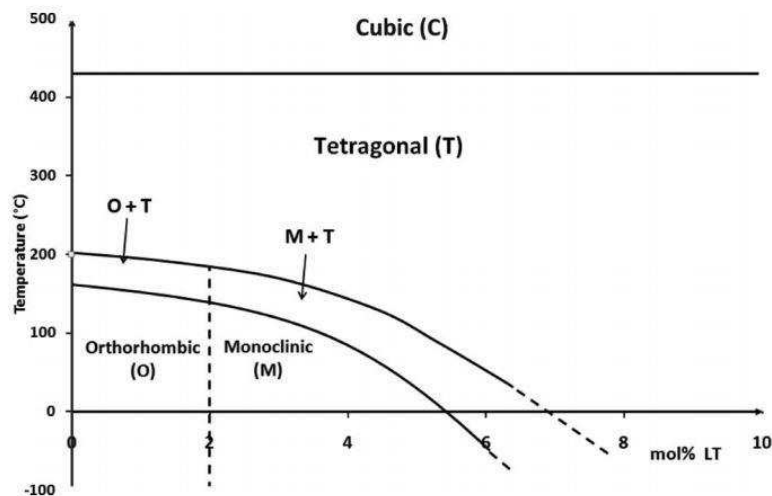


Figure 11. Phase diagram for the $\text{Na}_{0.5}\text{K}_{0.5}\text{NbO}_3\text{-LiTaO}_3$ system [57]

$\text{Na}_{0.5}\text{K}_{0.5}\text{NbO}_3\text{-LiTaO}_3\text{-BiScO}_3$

Skidmore et al., studied dielectric and piezoelectric properties in the ternary compositional system $(1-x)[(\text{Na}_{0.5}\text{K}_{0.5}\text{NbO}_3)_{0.93}\text{-(LiTaO}_3)_{0.07}]\text{-xBiScO}_3$ [59]. Addition of BiScO_3 led to a decrease in values of $\epsilon_{r \text{ max}}$ from ~ 3600 at $x = 0$ to ~ 1800 at $x = 0.02$ and the creation of a diffuse $\epsilon_r\text{-T}$ peak. The dielectric response become flatter at $x = 0.05$ with estimated ϵ_r values of $\sim 1150 \pm 15\%$ from $\sim 20^\circ\text{C}$ to 450°C [56, 59]; $\tan\delta$ values were 0.03–0.05 for temperatures from 20– 200°C , decreasing to < 0.025 at 200– 350°C [56].

Zhu et al., studied dielectric and piezoelectric properties in the system, $(1-x)[0.98\text{Na}_{0.5}\text{K}_{0.5}\text{NbO}_3\text{-}0.02\text{BiScO}_3]\text{-xLiTaO}_3$ [60, 61]. Values of $\epsilon_{r \text{ max}}$ decreased from an estimated 7000 at $x = 0$, to 2600 at $x = 0.03\text{LiTaO}_3$. Composition $x = 0.02 \text{LiTaO}_3$ showed consistent $\epsilon_r(\text{T})$ response with ϵ_r estimated at $1000 \pm 15\%$ from 0– 300°C . The $x = 0.03$ samples gave $\epsilon_r \sim 700 \pm 15\%$ from approximately $-55\text{--}200^\circ\text{C}$. Values of $\tan\delta$ were ~ 0.03 over these temperature ranges. For certain compositions, the broad $\epsilon_r\text{-T}$ response showed two sub-peaks. Analysis by TEM-EDX indicated the origin of the sub-peaks in certain $\text{Na}_{0.5}\text{K}_{0.5}\text{NbO}_3\text{-LiTaO}_3\text{-BiScO}_3$ compositions, e.g. $0.98[0.95\text{Na}_{0.5}\text{K}_{0.5}\text{NbO}_3\text{-}0.05\text{LiTaO}_3]\text{-}0.02\text{BiScO}_3$, was due to core-shell segregation [62].

$\text{K}_{0.5}\text{Na}_{0.5}\text{NbO}_3\text{-Bi(Zn}_{0.75}\text{W}_{0.25})\text{O}_3$

The solid solution $(1-x)\text{K}_{0.5}\text{Na}_{0.5}\text{NbO}_3\text{-xBi(Zn}_{0.75}\text{W}_{0.25})\text{O}_3$, [KNN-BZW] was synthesised by Chen et al. [63]. The crystal structure was identified as having orthorhombic symmetry with no evidence of secondary phases. Plots of $\epsilon_r\text{-T}$ indicated two phase transitions above room temperature: orthorhombic-tetragonal and tetragonal-cubic. These transitions became more diffuse with increasing BZW content. Composition $x = 0.01\text{BZW}$ gave temperature- stable dielectric behaviour, with $\epsilon_r \sim 1300 \pm 15\%$ from temperatures of 150 to 350°C ; $\tan\delta < 0.04$ across this temperature range.

3. Summary

A wide variety of compositionally complex perovskite solid solutions display near-stable relative permittivity over wide temperature ranges with upper temperature limits of stable ϵ_r ($\pm 15\%$) of $300\text{--}500^\circ\text{C}$. The properties of the most promising materials are summarised in Table 2; a graphical comparison of the best materials is shown in Figure 12. The materials with the widest temperature range of stable and high relative permittivity ($\epsilon_r \sim 1000$), low dielectric loss and high electrical resistivity in a single material are found in the $\text{Ba}_{0.8}\text{Ca}_{0.2}\text{TiO}_3\text{-Bi(Mg}_{0.5}\text{Ti}_{0.5})\text{O}_3$ and $\text{BaTiO}_3\text{-BiZn}_{0.5}\text{Ti}_{0.5}\text{O}_3\text{-BiScO}_3$ systems. However the lower temperature limit lies above room-temperature for these materials, which is restrictive for capacitor applications. Other materials which do achieve stability down to -55°C exhibit moderate relative permittivity values ($\epsilon_r \sim 500$). Therefore despite the advances in high temperature dielectric ceramics reviewed in this paper, further improvements in basic dielectric properties and working temperature ranges are required to bring the materials to a stage where they can be considered for further evaluation and implementation as practical high temperature capacitor materials. In addition, capacitor-grade testing including voltage stability and dielectric breakdown strength measurements will be required to confirm if a material is suitable for capacitor applications. At the time of writing this review, there is little published information on measurements of breakdown strengths performed according to statistically valid protocols. Ogiwara et al. applied a dc field to BT-BS samples of thickness 0.9 to 0.05 mm (ramp rate 500 V/s) reporting a current spike at $275 \pm 39 \text{ kV/cm}$ for a 0.48 mm thick sample (7 tested) and $764 \pm 52 \text{ kV/cm}$ for a 0.05 mm film (6 tested) [20]. In the

case of (1-x)BCT-xBMT, a preliminary study in collaboration with D A Hall at Manchester University indicted electrical breakdown to occur at 258 ± 30 kV/cm for 0.3 mm pellets and 204 ± 14 kV/cm for 0.5 mm pellets (10 tested at room temperature; ramp 500 V/s), but this type of measurement gives only an estimate of breakdown. The same BCT-BMT material ($x = 0.55$) under dc bias at a temperature of 180° retained a consistent value of relative permittivity of ~ 1200 at dc bias fields up to 4 kV/mm. This contrasts to the severe decrease in permittivity of ferroelectric materials under dc bias fields, and suggests temperature stable relaxors have promise in energy storage applications, provided breakdown strengths are sufficient (energy storage varies as $\epsilon_r E^2$) [64].

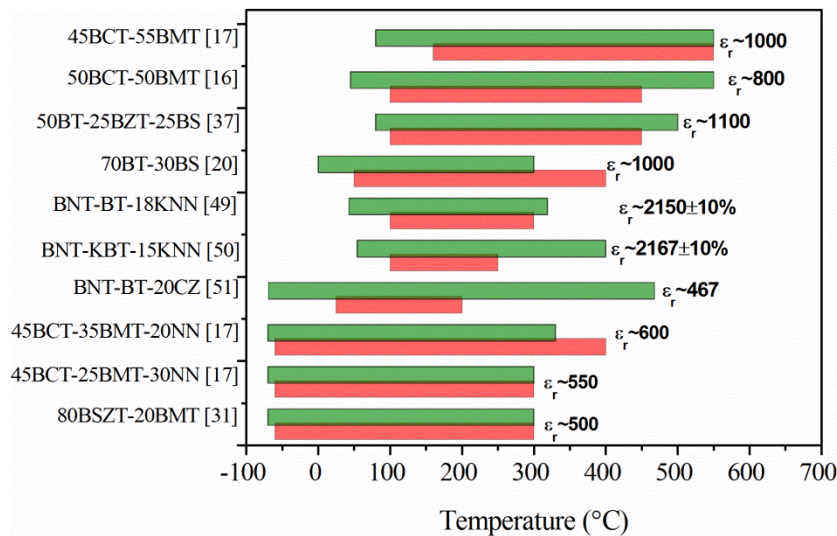


Figure 12. Bar plots representing temperature range of $\pm 15\%$ or better stability of ϵ_r (green bars): range of low $\tan \delta < 0.02$ represented by red bars.

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